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ON THE SYNTHESIS OF XENON(II) FLUOROSTANNATES(IV)

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SUMMARY

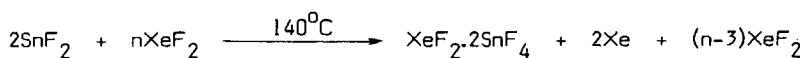
The reaction between tin difluoride and an excess of xenon difluoride at 140°C yields two new xenon(II) fluorostannates(IV): $3\text{XeF}_2 \cdot 4\text{SnF}_4$ and $\text{XeF}_2 \cdot 2\text{SnF}_4$. The 3:4 compound can be written as a molecular adduct of XeF_2 and the 1:2 compound. On the basis of vibrational spectra, the 1:2 compound can be formulated as a XeF^+ salt with a polymeric anion.

INTRODUCTION

The system xenon hexafluoride – tin fluorides has been extensively studied [1,2], which is not the case for the analogous system with xenon difluoride. It is known that SnF_4 forms addition compounds with electron donors, and therefore it was expected that XeF_2 would also form adducts with SnF_4 . So far, only the reaction between SnCl_4 and XeF_2 has been reported [3] and the adduct $2\text{XeF}_2 \cdot \text{SnF}_4$ was claimed on the basis of an infrared spectrum only. To obtain more data, the system XeF_2 – SnF_4 has been thoroughly investigated.

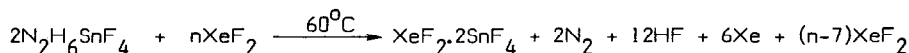
RESULTS AND DISCUSSION

To favour the formation of xenon difluoride rich complexes, we set out by treating tin difluoride with a large excess of liquid xenon difluoride. Xenon difluoride oxidized the Sn(II) forming xenon(II) fluorostannate(IV).



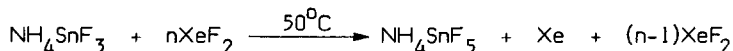
$n > 20$

The same compound could also be prepared using hydrazinium(2+) tetrafluorostannate(II) as starting material:



$n > 20$

The analogous reaction with ammonium trifluorostannate(II) proceeds at 50°C with only the formation of ammonium pentafluorostannate(IV) [4].



$n > 20$

A melt of XeF_2 at 130°C had to be used in order to prepare xenon(II) fluorostannate(IV).

During the preparation of $\text{XeF}_2 \cdot 2\text{SnF}_4$, the weight of the mixture in the reaction vessel was followed during the course of pumping off the volatiles. It was found that there is a change in the slope of the curve corresponding to the composition $3\text{XeF}_2 \cdot 4\text{SnF}_4$. This compound is not stable at room temperature and loses XeF_2 under dynamic vacuum at the rate of about 4 mole % per hour. The 3:4 compound can be isolated at 0°C .

It is interesting that the existence of the compound $2\text{XeF}_2 \cdot \text{SnF}_4$ [3] was not noticed even when very carefully recording the course of pumping off the volatiles at 0°C . It is possible that the compound claimed to be $2\text{XeF}_2 \cdot \text{SnF}_4$ was only $\text{XeF}_2 \cdot 2\text{SnF}_4$ with some impurities. In favour of this conclusion are the following facts: the published infrared spectrum of the compound reported to be $2\text{XeF}_2 \cdot \text{SnF}_4$ is practically identical with the infrared spectrum of our 1:2 compound, and the colour of the 2:1 compound is lemon yellow, whereas pure xenon(II) and xenon(VI) fluorostannates are all white solid materials [2].

$3\text{XeF}_2 \cdot 4\text{SnF}_4$ is a white diamagnetic solid with a negligible vapour pressure at 0°C . It loses XeF_2 slowly in dynamic vacuum at room temperature approaching the 1:2 composition, $\text{XeF}_2 \cdot 2\text{SnF}_4$, which is also a white diamagnetic solid with a negligible vapour pressure at room temperature.

Thermal decomposition of both xenon(II) fluorostannates(IV) is very simple. $3\text{XeF}_2 \cdot 4\text{SnF}_4$ starts to lose XeF_2 even below room temperature, while $\text{XeF}_2 \cdot 2\text{SnF}_4$ starts to lose XeF_2 at about 50°C . In both cases the final product at decomposition temperatures lower than 300°C is SnF_4 .

TABLE I

Vibrational spectra (cm^{-1}) of $3\text{XeF}_2 \cdot 4\text{SnF}_4$ and $\text{XeF}_2 \cdot 2\text{SnF}_4$

$3\text{XeF}_2 \cdot 4\text{SnF}_4$		$\text{XeF}_2 \cdot 2\text{SnF}_4$		Tentative assignments
IR	R	IR	R	
675 (m)		670 (m)		
625 (m)		627 (m)] $\nu(\text{Xe-F})$
	619 (38)		619 (43)	
	594 (66)	595 (sh)	594 (100)] $\nu(\text{Sn-F})$
582 (s)	588 (100)	585 (s)	580 (25)	
	574 (sh)			
550 (sh)		550 (vs)		
530 (vs)] νXeF_2
	509 (34)			
475 (s)		475 (s)] $\nu(\text{Sn-F})$
420 (sh)		420 (sh)		
	309 (2)] $\nu(\text{Xe} \cdots \text{F})$
	283 (2)		284 (2)	
	160 (12)		150 (18)	$\delta(\text{F-Xe} \cdots \text{F})$

Vibrational spectra of $3\text{XeF}_2 \cdot 4\text{SnF}_4$ and $\text{XeF}_2 \cdot 2\text{SnF}_4$ are shown in Table I. The Raman and infrared spectra of both compounds are very similar except for the Raman band at 509 cm^{-1} and the infrared absorption at 530 cm^{-1} in the 3:4 compound. This latter compound could be written as $\text{XeF}_2(\text{XeF}_2 \cdot 2\text{SnF}_4)_2$ which is a molecular adduct of XeF_2 and the 1:2 compound. This formulation explains the similarity of the two vibrational spectra and the thermal instability of the 3:4 compound, which loses XeF_2 in dynamic vacuum below room temperature forming $\text{XeF}_2 \cdot 2\text{SnF}_4$. The prominent Raman band at 509 cm^{-1} and the strong infrared band at 530 cm^{-1} are most probably the symmetric stretching vibration and the asymmetric stretching vibration of weakly associated molecular XeF_2 which in the free molecule is at 497 cm^{-1} and 547 cm^{-1} respectively.

Similar bands in the same region have been observed previously [5,6] and similarly attributed to 'weakly associated' molecular XeF_2 . The same phenomenon has also been observed in related krypton difluoride adducts [7,8].

Vibrational spectra of $3\text{XeF}_2 \cdot 4\text{SnF}_4$ and $\text{XeF}_2 \cdot 2\text{SnF}_4$ provide evidence of an XeF^+ species, which is characterized in the $\text{XeF}^+\text{MF}_6^-$ and $\text{XeF}^+\text{M}_2\text{F}_{11}^-$ salts by a band or pair of bands in the Raman spectrum in the $621\text{--}598\text{ cm}^{-1}$ region [9], and in the infrared spectrum in the $626\text{--}600\text{ cm}^{-1}$ region [5]. The occurrence of a band at 619 cm^{-1} in both Raman spectra, and bands at 625 cm^{-1} and 627 cm^{-1} in the infrared spectra of the 3:4 and 1:2 compounds, respectively, suggests the presence of XeF^+ species.

It is very unlikely that the anion is Sn_2F_9^- , since octahedral coordination of Sn is anticipated, and face-sharing of two octahedra has never been confirmed for any polyfluoro metal species. There are two other possibilities: firstly that we have an infinite polymer as in noble metal pentafluoride or tetrafluoride structures [10], or secondly that we have discrete species, the simplest of which we would expect to be $\text{Sn}_8\text{F}_{36}^{4-}$ [11]. Tin is considered to be octahedrally coordinated to the fluorine atoms (3 uniquely, 3 bridging). The same fluorine bridged polymeric anion was also proposed in the analogous compound between xenon hexafluoride and tin tetrafluoride $3\text{XeF}_6 \cdot 4\text{SnF}_4$ [2]. The vibrational spectra of this compound do not show anion lines below 400 cm^{-1} , and therefore the bands appearing in this region in the vibrational spectra of $\text{XeF}_2 \cdot 2\text{SnF}_4$ were assigned to stretching and bending modes of the xenon-fluorine bridge.

EXPERIMENTAL

General apparatus and techniques. The products were synthesized in argon arc welded nickel pressure and weighing vessels, equipped with Teflon-packed nickel valves. The volume of the reaction vessels was about 100 cm^3 . The reaction vessels were hydrostatically tested up to 20 MPa. Transfer of all materials was carried out either in the atmosphere of a dry box, or by distillation under vacuum in well dried apparatus.

Raman spectra were recorded using a Spex 1401 double monochromated instrument. As exciting radiation, the $514,5\text{ nm}$ line of an Ar^+ laser (Coherent Radiation) was used. Powdered samples were loaded into quartz capillaries in a dry box and temporarily plugged with Kel-F grease. They were sealed with a small flame outside the dry box.

Infrared spectra were recorded using a Zeiss UR-20 spectrometer. A 10 cm path length nickel cell with silver chloride windows was used for gas phase work. Spectra of solids were obtained by dusting samples onto silver chloride plates sandwiched in a leak-tight brass holder.

X-ray powder photographs were obtained by the Debye-Scherrer method on an ENRAF apparatus (Delft, Holland) using graphite monochromated $\text{CuK}\alpha$ radiation. Finely powdered samples were sealed in 0.5 mm thin-walled quartz capillaries.

Thermal analyses were carried out on a Mettler TA-1 Thermoanalyzer under the following experimental conditions: low temperature furnace heating rate $4^\circ\text{C}/\text{min}$; argon atmosphere with a flow rate $5 \text{ dm}^3/\text{h}$; Pt or alumina crucibles. The sample weight was 100 mg and the reference substance was $\alpha\text{-Al}_2\text{O}_3$. Some thermal decompositions were also carried out in the nickel reaction vessel on several-gram quantities of the sample.

The magnetic susceptibility was measured using the Faraday method on a modified Newport Instrument magnetic balance. The magnetic field was calibrated using $\text{HgCo}(\text{CNS})_4$. The powdered sample was packed into a thin-walled screw-capped Kel-F container (4 mm o.d., 4 mm height).

Reagents. Tin(II) fluoride, 99.99% was from Ventron Alfa Products (ultrapure). $\text{N}_2\text{H}_6\text{SnF}_4$ was prepared as described elsewhere [12]. Xenon difluoride was prepared by photosynthesis [13].

Preparation. The compound $\text{XeF}_2 \cdot 2\text{SnF}_4$ was prepared by reaction between SnF_2 and excess xenon difluoride at 140°C . After the reaction ceased, the xenon formed was pumped off at -80°C , while excess of xenon difluoride was removed at room temperature.

The compound $\text{XeF}_2 \cdot 2\text{SnF}_4$ was also prepared by reaction between $\text{N}_2\text{H}_6\text{SnF}_4$ and excess xenon difluoride at 60°C . After the reaction was complete, the reaction products, nitrogen, xenon, hydrogen fluoride and excess xenon difluoride, were pumped away at -196°C , -80°C , -50°C , and at room temperature, respectively.

$3\text{XeF}_2 \cdot 4\text{SnF}_4$ was isolated by pumping off excess XeF_2 at 0°C .

The stoichiometry of the reactions was also followed by weighing the reactants and products with an accuracy of $\pm 1 \text{ mg}$ throughout the experiments (Table 2).

TABLE 2

Mass analysis of xenon(II) fluorostannates(IV)

Run	Mass of SnF_2 and $\text{N}_2\text{H}_6\text{SnF}_4$ (g)	Mass of the products		Difference (%)
		Calcd. (g)	Found (g)	
$\text{SnF}_2 + n\text{XeF}_2 \rightarrow \text{XeF}_2 \cdot 2\text{SnF}_4$	0.8529	1.5196	1.5398	1.3
$\text{SnF}_2 + n\text{XeF}_2 \rightarrow \text{XeF}_2 \cdot 2\text{SnF}_4$	0.5223	0.9302	0.9370	0.7
$\text{SnF}_2 + n\text{XeF}_2 \rightarrow \text{XeF}_2 \cdot 2\text{SnF}_4$	0.5308	0.9489	0.9664	1.8
$\text{SnF}_2 + n\text{XeF}_2 \rightarrow 3\text{XeF}_2 \cdot 4\text{SnF}_4$	0.7089	1.4476	1.4632	1.1
$\text{N}_2\text{H}_6\text{SnF}_4 + n\text{XeF}_2 \rightarrow \text{XeF}_2 \cdot 2\text{SnF}_4$	0.5936	0.7263	0.7402	1.9

The xenon(II) fluorostannates(IV) were examined by X-ray powder photography, Raman and Infrared spectroscopy, magnetic susceptibility measurements and were chemically analysed.

Calcd. for $\text{XeF}_2 \cdot 2\text{SnF}_4$: F, 34.01%; Sn, 42.49%; Xe, 23.50%
 Found F, 34.3 %; Sn, 41.9 %; Xe, 24.2 %

Calcd. for $3\text{XeF}_2 \cdot 4\text{SnF}_4$: F, 32.69%; Sn, 36.51%; Xe, 30.80%
 Found F, 32.2 %; Sn, 37.1 %; Xe, 30.0 %

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